

CDCDB800 PCIe Gen 1~Gen 6 向け DB800ZL 準拠 8 出力クロック・バッファ

1 特長

- 8 つの LP-HCSL 出力、プログラム可能な内蔵 85Ω (デフォルト) または 100Ω 差動出力終端付き
- 8 つのハードウェア出力イネーブル (OE#) 制御
- PCIe Gen 6 フィルタ後の付加位相ジッタ: 20fs RMS (最大値)
- PCIe Gen 5 フィルタ後の付加位相ジッタ: 25fs RMS (最大値)
- DB2000Q フィルタ後の付加位相ジッタ: 38fs RMS (最大値)
- 共通クロック (CC) アーキテクチャと個別リファレンス (IR) アーキテクチャをサポート
 - スペクトラム拡散対応
- 出力間スキュー: <50ps
- 入出力間遅延: <3ns
- フェイルセーフ入力
- プログラム可能な出力スルーレート制御
- コアおよび入出力電源電圧: 3.3V
- ハードウェア制御による低消費電力モード (PD#)
- 消費電流: 72mA (最大値)
- 6mm × 6mm、48 ピン VQFN パッケージ

2 アプリケーション

- マイクロサーバー / タワー・サーバー
- ストレージ・エリア・ネットワーク (SAN) およびホスト・バス・アダプタ (HBA) カード
- ネットワーク接続ストレージ (NAS)
- ハードウェア・アクセラレータ
- ラック・サーバー

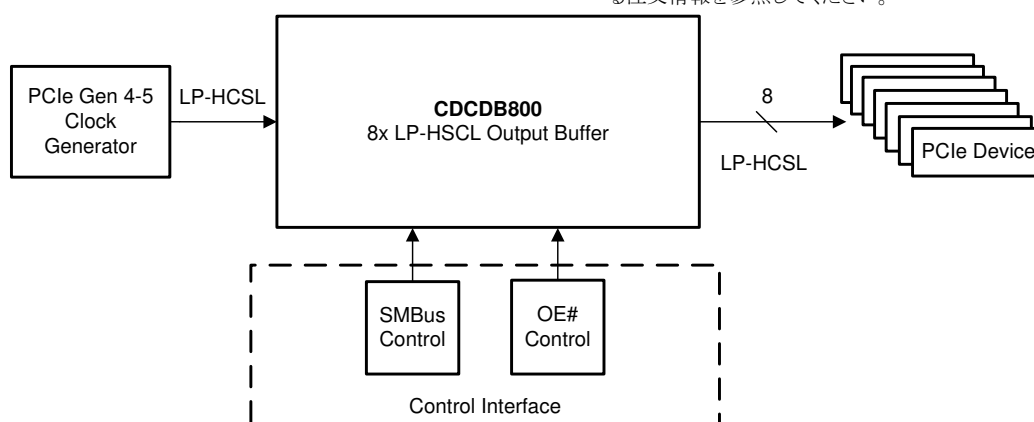
3 説明

CDCDB800 は、PCIe Gen 1 ~ 6、QuickPath Interconnect (QPI)、UPI、SAS、SATA インターフェイス用のリファレンス・クロックを分配できる 8 出力 LP-HCSL、DB800ZL 準拠クロック・バッファです。SMBus インターフェイスおよび 8 本の出力イネーブル・ピンにより、8 個の出力すべてを個別に設定および制御できます。CDCDB800 は DB800ZL から派生したバッファであり、DB800ZL 仕様のシステム・パラメータと同等またはそれを上回る性能を備えています。また、DB2000Q 仕様のパラメータと同等またはそれを上回る性能も備えています。CDCDB800 は、6mm × 6mm の 48 ピン VQFN パッケージで供給されません。

製品情報

部品番号	パッケージ ⁽¹⁾	本体サイズ (公称)
CDCDB800	VQFN (48)	6.00mm × 6.00mm

(1) 利用可能なパッケージについては、このデータシートの末尾にある注文情報を参照してください。



CDCDB800 システム図



Table of Contents

1 特長	1	8.5 Programming.....	14
2 アプリケーション	1	8.6 Register Maps.....	16
3 説明	1	9 Application and Implementation	20
4 Revision History	2	9.1 Application Information.....	20
5 Pin Configuration and Functions	3	9.2 Typical Application.....	20
6 Specifications	6	10 Power Supply Recommendations	22
6.1 Absolute Maximum Ratings	6	11 Layout	23
6.2 ESD Ratings	6	11.1 Layout Guidelines.....	23
6.3 Recommended Operating Conditions	6	11.2 Layout Examples.....	23
6.4 Thermal Information	6	12 Device and Documentation Support	25
6.5 Electrical Characteristics	7	12.1 Device Support.....	25
6.6 Timing Requirements	9	12.2 Receiving Notification of Documentation Updates.....	25
6.7 Typical Characteristics.....	10	12.3 サポート・リソース.....	25
7 Parameter Measurement Information	11	12.4 Trademarks.....	25
8 Detailed Description	12	12.5 Electrostatic Discharge Caution.....	25
8.1 Overview.....	12	12.6 Glossary.....	25
8.2 Functional Block Diagram.....	12	13 Mechanical, Packaging, and Orderable Information	25
8.3 Feature Description.....	12		
8.4 Device Functional Modes.....	13		

4 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

Changes from Revision A (September 2021) to Revision B (May 2022)	Page
• データシートのタイトルを更新.....	1
• データシートに PCIe Gen 6 を追加.....	1
• Changed the pin description for pin 46	3

Changes from Revision * (July 2021) to Revision A (September 2021)	Page
• Changed pin descriptions for pins 47 and 48.....	3
• Changed <i>Absolute Maximum Ratings</i> note 1.....	6
• Changed the SPI terminology for the generic programming sequence and protocol figures	14
• Changed the reset values and description for the <i>Register Field Description</i> tables.....	16

5 Pin Configuration and Functions

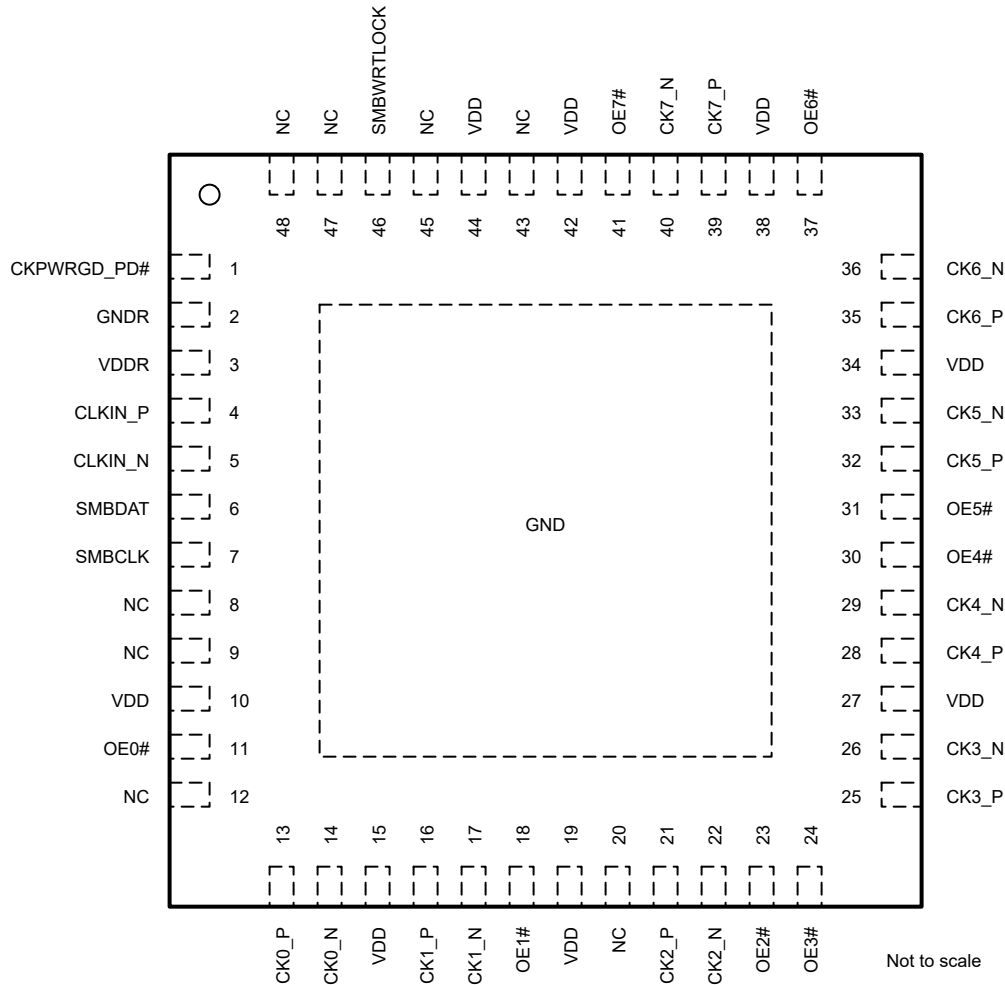


图 5-1. CDCDB800 RSL Package 48-Pin VQFN Top View

表 5-1. Pin Functions CDCDB800

PIN		TYPE ⁽²⁾	DESCRIPTION
NAME	NO.		
INPUT CLOCK			
CLKIN_P	4	I	LP-HCSL differential clock input. Typically connected directly to the differential output of clock source.
CLKIN_N	5	I	
OUTPUT CLOCKS			
CK0_P	13	O	LP-HCSL differential clock output of channel 0. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK0_N	14	O	
CK1_P	16	O	LP-HCSL differential clock output of channel 1. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK1_N	17	O	

表 5-1. Pin Functions CDCDB800 (continued)

PIN		TYPE ⁽²⁾	DESCRIPTION
NAME	NO.		
CK2_P	21	O	LP-HCSL differential clock output of channel 2. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK2_N	22	O	
CK3_P	25	O	LP-HCSL differential clock output of channel 3. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK3_N	26	O	
CK4_P	28	O	LP-HCSL differential clock output of channel 4. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK4_N	29	O	
CK5_P	32	O	LP-HCSL differential clock output of channel 5. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK5_N	33	O	
CK6_P	35	O	LP-HCSL differential clock output of channel 6. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK6_N	36	O	
CK7_P	39	O	LP-HCSL differential clock output of channel 7. Typically connected directly to PCIe differential clock input. If unused, the pins can be left no connect.
CK7_N	40	O	
MANAGEMENT AND CONTROL ⁽¹⁾			
CKPWRGD_PD#	1	I, S, PD	Clock Power Good and Power Down multi-function input pin with internal 180-kΩ pulldown. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. After PWRGD has been asserted high for the first time, the pin becomes a PD# pin and it controls power-down mode: LOW: Power-down mode, all output channels tri-stated. HIGH: Normal operation mode.
OE0#	11	I, S, PD	Output Enable for channel 0 with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 0. HIGH: disable output channel 0.
OE1#	18	I, S, PD	Output Enable for channel 1 with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 1. HIGH: disable output channel 1.
OE2#	23	I, S, PD	Output Enable for channel 2 with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 2. HIGH: disable output channel 2.
OE3#	24	I, S, PD	Output Enable for channel 3, with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 3. HIGH: disable output channel 3.
OE4#	30	I, S, PD	Output Enable for channel 4, with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 4. HIGH: disable output channel 4.
OE5#	31	I, S, PD	Output Enable for channel 5, with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 5. HIGH: disable output channel 5.
OE6#	37	I, S, PD	Output Enable for channel 6 with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 6. HIGH: disable output channel 6.
OE7#	41	I, S, PD	Output Enable for channel 7 with internal 180-kΩ pulldown, active low. Typically connected to GPIO of microcontroller. If unused, the pin can be left no connect. LOW: enable output channel 7. HIGH: disable output channel 7.
SMBUS AND SMBUS ADDRESS			

表 5-1. Pin Functions CDCDB800 (continued)

PIN		TYPE ⁽²⁾	DESCRIPTION
NAME	NO.		
SMBDAT	6	I / O	Data pin of SMBus interface. Typically pulled up to 3.3-V VDD using external pullup resistor. The recommended pullup resistor value is > 8.5k.
SMBCLK	7	I	Clock pin of SMBus interface. Typically pulled up to 3.3-V VDD using external pullup resistor. The recommended pullup resistor value is > 8.5k.
SMBWRTLOCK	46	I, PD	SMBWRTLOCK: Disables write commands on SMBus. All writes will be ignored when SMBWRTLOCK is asserted (reads are not affected). Internal 180-kΩ pulldown, active high. 0 = SMBus write enabled. 1 = SMBus write disabled.
SUPPLY VOLTAGE AND GROUND			
GNDR	2	G	Ground.
VDDR	3	P	Power supply input for input clock receiver. Connect to 3.3-V power supply rail with decoupling capacitor to GND. Place a 0.1-μF capacitor close to each supply pin between power supply and ground.
VDD	10, 15, 19, 27, 34, 38, 42, 44	P	3.3-V power supply for output channels and core voltage.
GND	DAP	G	Ground. Connect ground pad to system ground.
NO CONNECT			
NC	8, 9, 12, 20, 43, 45	—	Do not connect to GND or VDD.
NC	47, 48	—	No connect. Pins may be connected to GND, VDD, or otherwise tied to any potential within the Supply Voltage range stated in the Absolute Maximum Ratings.

- (1) The “#” symbol at the end of a pin name indicates that the active state occurs when the signal is at a low voltage level. When “#” is not present, the signal is active high.
- (2) The definitions below define the I/O type for each pin.
- I = Input
 - O = Output
 - I / O = Input / Output
 - PU / PD = Internal 180-kΩ Pullup / Pulldown network biasing to VDD/2
 - PD = Internal 180-kΩ Pulldown
 - S = Hardware Configuration Pin
 - P = Power Supply
 - G = Ground

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{DD} , V _{DD_R}	Power supply voltage	-0.3	3.6	V
V _{IN}	IO input voltage	-0.3	3.6	V
T _J	Junction temperature		125	°C
T _{stg}	Storage temperature	-65	150	°C

- (1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. *Absolute Maximum Ratings* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If used outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±3500	V
		Charged device model (CDM), per JEDEC specification JESD22-C101, all pins ⁽²⁾	±1000	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
 (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{DD}	IO, Core supply voltage	3	3.3	3.6	V
V _{DD_R}	Input supply voltage	3	3.3	3.6	V
T _A	Ambient temperature	-40		105	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		Device Package	UNIT
		RSL (QFN)	
		48 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	32.2	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	22.3	°C/W
R _{θJB}	Junction-to-board thermal resistance	14.3	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	0.5	°C/W
Ψ _{JB}	Junction-to-board characterization parameter	14.2	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	6.1	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Electrical Characteristics

VDD, VDD_R = 3.3 V ± 5 %, -40°C ≤ T_A ≤ 105°C. Typical values are at VDD = VDD_R = 3.3 V, 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
CURRENT CONSUMPTION						
I _{DD_R}	Core supply current	Active mode. CKPWRGD_PD# = 1			9	mA
		Power-down mode. CKPWRGD_PD# = 0			2.2	
I _{DD}	IO supply current	All outputs disabled			18	mA
		All outputs active, 100MHz (Per output)			7.8	
		Power-down mode. CKPWRGD_PD# = 0			1.5	
CLOCK INPUT						
f _{IN}	Input frequency		50	100	250	MHz
V _{IN}	Input voltage swing	Differential voltage between CLKIN_P and CLKIN_N ⁽¹⁾	200		2300	mV _{Diff-peak}
dV/dt	Input voltage edge rate	20% - 80% of input swing	0.7			V/ns
DV _{CROSS}	Total variation of V _{CROSS}	Total variation across V _{CROSS}		140		mV
DC _{IN}	Input duty cycle		40		60	%
C _{IN}	Input capacitance ⁽²⁾	Differential capacitance between CLKIN_P and CLKIN_N pins		2.2		pF
CLOCK OUTPUT						
f _{OUT}	Output frequency		50	100	250	MHz
C _{OUT}	Output capacitance ⁽¹⁾	Differential capacitance between CKx_P and CKx_N pins		4		pF
V _{OH}	Output high voltage	Single-ended ^{(2) (3)}	225		270	mV
V _{OL}	Output low voltage		10		150	
V _{HIGH}	Output high voltage	Measured into an AC load as defined in DB800ZL	660		850	
V _{LOW}	Output low voltage	Measured into an AC load as defined in DB800ZL	-150		150	
V _{MAX}	Output Max voltage	Measured into an AC load as defined in DB800ZL			1150	
V _{CROSS}	Crossing point voltage	^{(3) (4)}	130		200	
V _{CROSSAC}	Crossing point voltage (AC load)	Measured into an AC load as defined in DB800ZL	250		550	
DV _{CROSS}	Total variation of V _{CROSS}	Variation of V _{CROSS} ^{(3) (4)}		35	140	
V _{ovs}	Overshoot voltage	⁽³⁾			V _{OH} +75	
V _{ovs(AC)}	Overshoot voltage (AC load)	Measured into an AC load as defined in DB800ZL			V _{HIGH} +30 0	
V _{uds}	Undershoot voltage	⁽³⁾			V _{OL} -75	
V _{uds(AC)}	Undershoot voltage	Measured into an AC load as defined in DB800ZL			V _{LOW} - 300	
V _{rb}	Ringback Voltage	Measured into an AC load as defined in DB800ZL and taken from Single Ended waveform (relative to V _{HIGH} and V _{LOW})	-0.2		0.2	V
Z _{DIFF}	Differential impedance (Default setting, 85 Ω)	Measured at V _{OL} /V _{OH}	81	85	89	Ω
	Differential impedance (Output impedance selection bit =1, 100 Ω)	Measured at V _{OL} /V _{OH}	95	100	105	
Z _{DIFF_CROSS}	Differential impedance (Default setting, 85 Ω)	Measured at V _{CROSS}	68	85	102	
	Differential impedance (Output impedance selection bit = 1, 100 Ω)	Measured at V _{CROSS}	80	100	120	

CDCDB800

JAJSK44B – JULY 2021 – REVISED MAY 2022

 VDD, VDD_R = 3.3 V ± 5 %, -40°C ≤ T_A ≤ 105°C. Typical values are at VDD = VDD_R = 3.3 V, 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t _{EDGE}	Differential edge rate	Measured (+/-150 mV) around V _{CROSS} ⁽⁷⁾		2		4	V/ns
D _{tEDGE}	Edge rate matching	Measured (+/-75 mV) V _{CROSS} ⁽⁷⁾				20	%
t _{STABLE}	Power good assertion to stable clock output	CKPWRGD_PD# pin transitions from 0 to 1, f _{IN} = 100 MHz	Measured when positive output reaches 0.2V			1.8	ms
t _{DRIVE_PD#}	Power good assertion to outputs driven high	CKPWRGD_PD# pin transitions from 0 to 1, f _{IN} = 100 MHz	Measured when positive output reaches 0.2V			300	µs
t _{OE}	Output enable assertion to stable clock output	OEx# pin transitions from 1 to 0				10	CLKIN Periods
t _{OD}	Output enable de-assertion to no clock output	OEx# pin transitions from 0 to 1				10	
t _{PD}	Power-down assertion to no clock output	CKPWRGD_PD# pin transitions from 1 to 0				3	
t _{DCD}	Duty cycle distortion	Differential; f _{IN} = 100MHz, f _{IN_DC} = 50%		-1		1	%
t _{DLY}	Propagation delay	⁽⁵⁾		0.5		3	ns
t _{SKREW}	Skew between outputs	⁽⁶⁾				50	ps
t _{DELAY(IN-OUT)}	Input to output delay variation	Input-to-output delay variation at 100 MHz across voltage and temperature		-250		250	ps
J _{CKX_DB2000Q} ⁽⁷⁾	Additive jitter for DB2000Q	DB2000Q filter, for input of 200 mV differential swing @ 1.5 V/ns				0.038	ps, RMS
J _{CKX_PCIE} ⁽⁷⁾	Additive jitter for PCIe6.0	PLL BW: 0.5 - 1 MHz; CDR = 10 MHz	Input clock slew rate = 2 V/ns			0.02	ps, RMS
	Additive jitter for PCIe5.0	PCIe5.0 filter				0.025	
	Additive jitter for PCIe4.0	PLL BW = 2 - 5 MHz; CDR = 10 MHz	Input clock slew rate ≥ 1.8 V/ns			0.06	
	Additive jitter for PCIe3.0		Input clock slew rate ≥ 0.6 V/ns			0.1	
J _{CKX}	Additive jitter	f _{IN} = 100 MHz; slew rate ≥ 3 V/ns; 12 kHz to 20 MHz integration bandwidth.			100	160	fs, RMS
NF	Noise floor	f _{IN} = 100 MHz; f _{Offset} ≥ 10 MHz	Input clock slew rate ≥ 3 V/ns		-160	-155	dBc/Hz
SMBUS INTERFACE, OEx#, CKPWRGD_PD#							
V _{IH}	High level input voltage			2.0			V
V _{IL}	Low level input voltage					0.8	
I _{IH}	Input leakage current	With internal pull-up/pull-down	GND ≤ V _{IN} ≤ V _{DD}	-30		30	µA
I _{IL}	Input leakage current	With internal pull-up/pull-down	GND ≤ V _{IN} ≤ V _{DD}	-30		30	µA
I _{IH}	Input leakage current	Without internal pull-up/pull-down	GND ≤ V _{IN} ≤ V _{DD}	-5		5	µA
I _{IL}	Input leakage current	Without internal pull-up/pull-down	GND ≤ V _{IN} ≤ V _{DD}	-5		5	µA

VDD, VDD_R = 3.3 V ± 5 %, -40°C ≤ T_A ≤ 105°C. Typical values are at VDD = VDD_R = 3.3 V, 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
C _{IN}	Input capacitance				4.5		pF
C _{OUT}	Output capacitance				4.5		pF
I _{IH}	Input leakage current	With internal pull-up/pull-down	V _{IN} = V _{DD}	-30		30	μA
C _{IN}	Input capacitance ⁽¹⁾				4.5		pF

- (1) Voltage swing includes overshoot.
- (2) Not tested in production. Ensured by design and characterization.
- (3) Measured into DC test load.
- (4) V_{CROSS} is single-ended voltage when CKx_P = CKx_N with respect to system ground. Only valid on rising edge of CKx, when CKx_P is rising.
- (5) Measured from rising edge of CLK_IN to any CKx output.
- (6) Measured from rising edge of any CKx output to any other CKx output.
- (7) Measured into AC test load.

6.6 Timing Requirements

VDD, VDD_R = 3.3 V ± 5 %, -40°C ≤ T_A ≤ 105°C. Typical values are at VDD = VDD_A = 3.3 V, 25°C (unless otherwise noted)

			MIN	NOM	MAX	UNIT
SMBUS-COMPATIBLE INTERFACE TIMING						
f _{SMB}	SMBus operating frequency		10		400	kHz
t _{BUF}	Bus free time between STOP and START		4.7			μs
t _{HD_STA}	START condition hold time	SMBCLK low after SMBDAT low	4			
t _{SU_STA}	START condition setup time	SMBCLK high before SMBDAT low	4.7			
t _{SU_STO}	STOP condition setup time		4			
t _{HD_DAT}	SMBDAT hold time		300			ns
t _{SU_DAT}	SMBDAT setup time		250			
t _{TIMEOUT}	Detect SMBCLK low timeout	In terms of device input clock frequency	1e6			cycles
t _{LOW}	SMBCLK low period		4.7			μs
t _{HIGH}	SMBCLK high period		4		50	
t _F	SMBCLK/SMBDAT fall time ⁽¹⁾				300	ns
t _R	SMBCLK/SMBDAT rise time ⁽²⁾				1000	

- (1) TF = (VIHMIN + 0.15) to (VILMAX - 0.15)
- (2) TR = (VILMAX - 0.15) to (VIHMIN + 0.15)

6.7 Typical Characteristics

Figure 6-1 shows both the phase noise of the source as well as the output of the DUT (CDCDB800). It can be seen from the phase noise plot that the DUT has a very low phase noise profile with total jitter of 71 fs, rms. If we rms subtract the clock reference noise, the additive jitter of CDCDB800 under typical conditions would be lower than 71 fs, rms.

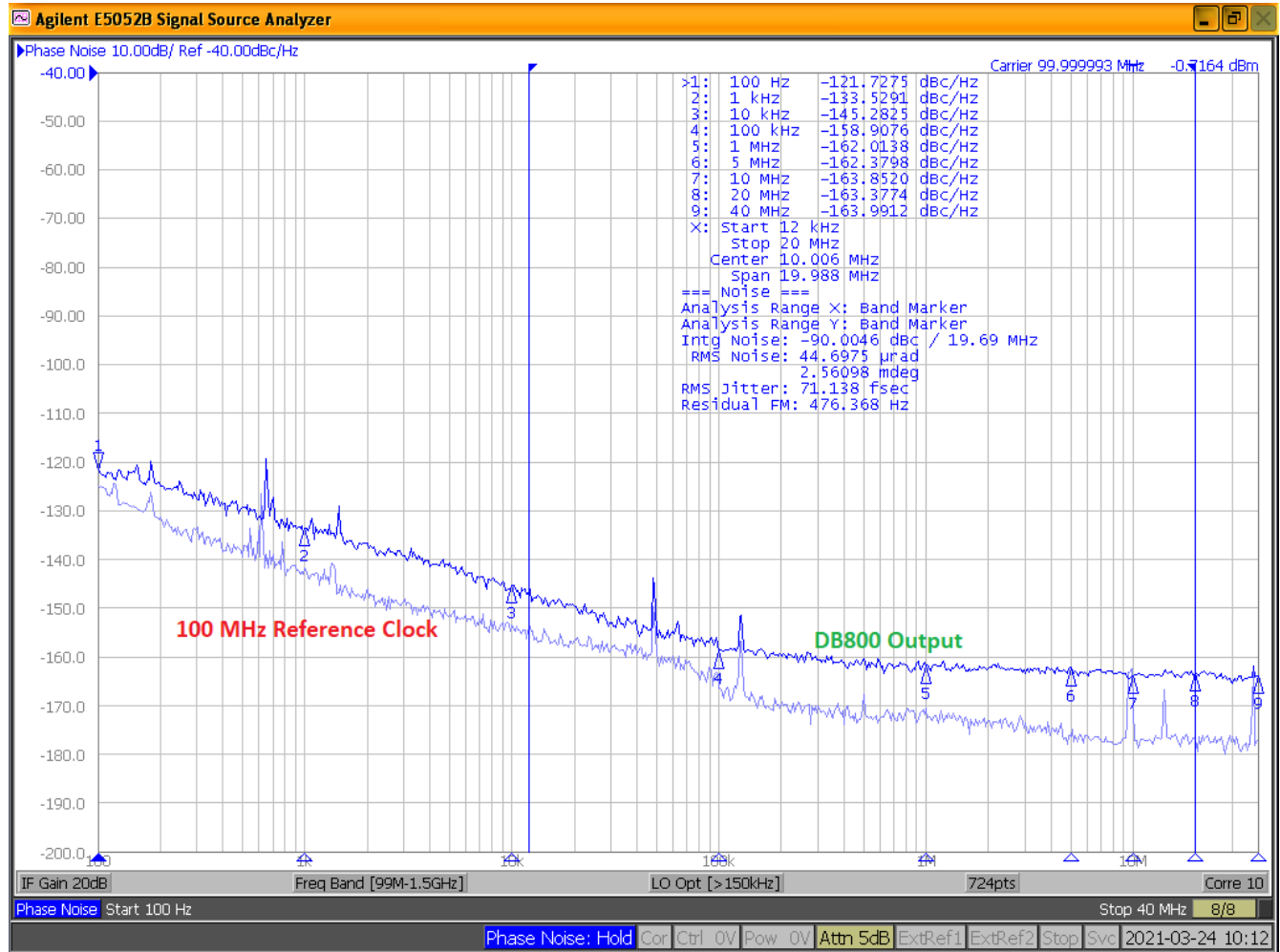
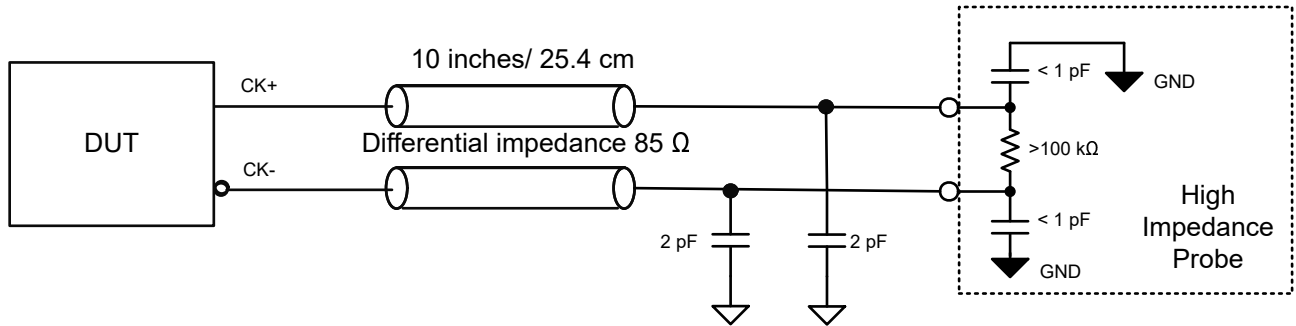
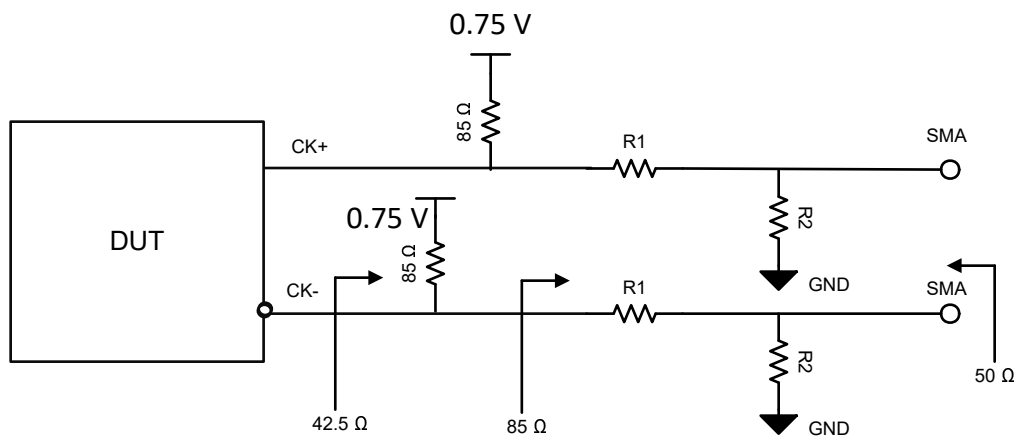


Figure 6-1. CDCDB800 Clock Out (CK0:8) Phase Noise

7 Parameter Measurement Information



 7-1. AC Test Load (Referencing Intel DB2000QL Document)



$R1 = 47\ \Omega$ and $R2 = 147\ \Omega$.

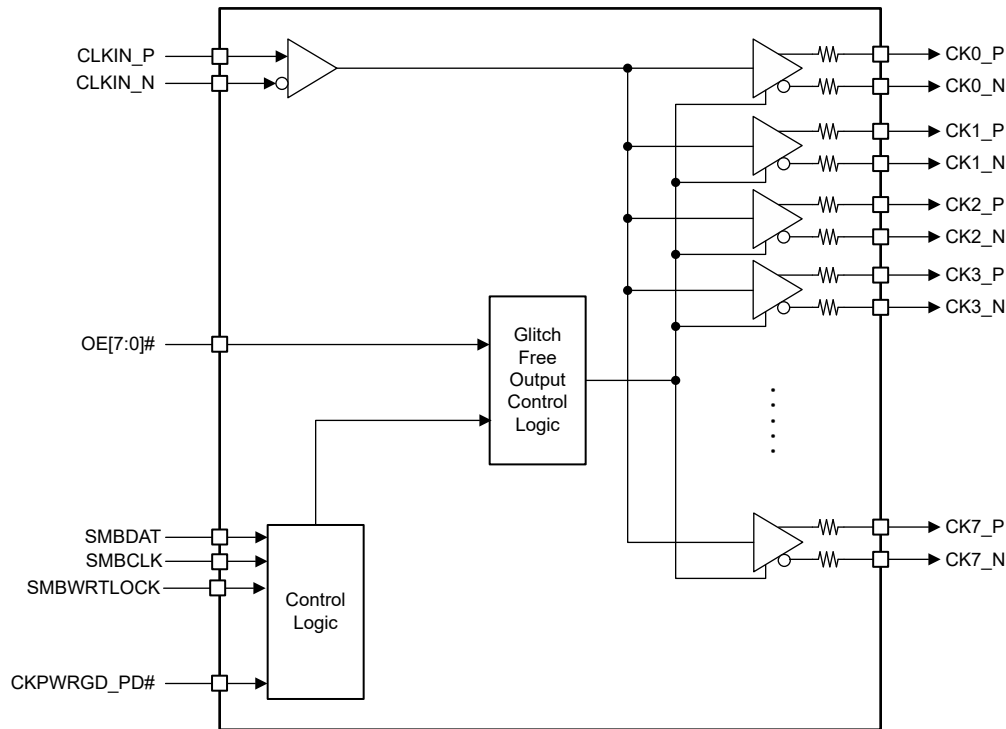
 7-2. DC Simulation Load (Referencing Intel DB2000QL Document)

8 Detailed Description

8.1 Overview

The CDCDB800 is a low additive-jitter, low propagation delay clock buffer designed to meet the strict performance requirements for PCIe Gen 1-6, QPI, UPI, SAS, and SATA reference clocks. The CDCDB800 allows buffering and replication of a single clock source to up to eight individual outputs in the LP-HCSL format. The CDCDB800 also includes status and control registers accessible by an SMBus version 2.0 compliant interface. The device integrates a large amount of external passive components to reduce overall system cost.

8.2 Functional Block Diagram



8.3 Feature Description

8.3.1 Fail-Safe Input

The CDCDB800 is designed to support fail-safe input operation feature. This feature allows the user to drive the device inputs before V_{DD} is applied without damaging the device. Refer to the [Absolute Maximum Ratings](#) table for more information on the maximum input supported by the device.

8.3.2 Output Enable Control

The CDCDB800 uses SMBus and OE# to control the state of the output channels. The OE# pins control the state of the output with the same number. For example, the OE5# pin controls the state of the CK5 output driver. The SMBus registers may enable or disable the output when the corresponding OE# pin is held low.

8.3.3 SMBus

The CDCDB800 has an SMBus interface that is active only when CKPWRGD_PD# = 1. The SMBus allows individual enable/disable of each output.

When CKPWRGD_PD# = 0, the SMBus pins are placed in a Hi-Z state, but all register settings are retained. The SMBus register values are only retained while V_{DD} remains inside of the recommended operating voltage.

8.3.3.1 SMBus Address Assignment

The CDCDB800 responds to SMBus address of 0xD8 for write operations (Read/Write = 0), and 0xD9 for read operations (Read/Write = 1).

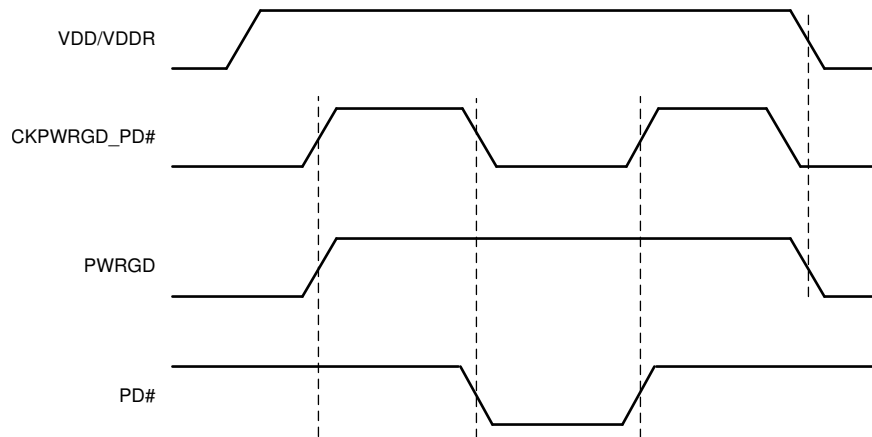
8.4 Device Functional Modes

8.4.1 CKPWRGD_PD# Function

The CKPWRGD_PD# pin is used to set two state variables inside of the device: PWRGD and PD#. The PWRGD and PD# variables control which functions of the device are active at any time, as well as the state of the input and output pins.

The PWRGD and PD# states are multiplexed on the CKPWRGD_PD# pin. CKPWRGD_PD# must remain below V_{OL} and not exceed $V_{DDR} + 0.3\text{ V}$ until V_{DD} and V_{DDR} are present and within the recommended operating conditions. After CKPWRGD_PD# is set high, a valid CLKIN must be present to use PD#.

The first rising edge of the CKPWRGD_PD# pin sets PWRGD = 1. After PWRGD is set to 1, the CKPWRGD_PD# pin is used to assert PD# mode only. PWRGD variable will only be cleared to 0 with the removal of V_{DD} and V_{DDR} .



8-1. PWRGD and PD# State Changes

8.4.2 OE[7:0]# and SMBus Output Enables

Each output channel, 0 to 7, can be individually enabled or disabled by a SMBus control register bit, called SMB enable bits. Additionally, each output channel has a dedicated, corresponding, OE[7:0]# hardware pin. The OE[7:0]# pins are asynchronously asserted-low signals that may enable or disable the output.

Refer to 表 8-1 for enabling and disabling outputs through the hardware and software. Note that both the SMB enable bit must be a 1 and the OEx# pin must be an input low voltage 0 for the output channel to be active.

表 8-1. OE[7:0]# Functionality

Control Inputs	Power State Variables (Internal)		CLKIN	OE[7:0]# HARDWARE PINS AND SMBus CONTROL REGISTER BITS			CK[7:0]_P/ CK[7:0]_N
	CKPWRGD_PD#	PWRGD		PD#	OE[7:0]#	OUT_EN_CLK[7:0]	
0	0	0	X	X	X	X	LOW/LOW
1	1	1	X ⁽¹⁾	X	0	0	LOW/LOW
						1	TRI-STATE
				1	X	0	LOW/LOW
			Running ⁽¹⁾	0	1	X	1
0		0	X ⁽²⁾	X	X	0	LOW/LOW
						1	TRI-STATE

(1) To enter the power-down state, CLKIN must remain active for at least 3 clock cycles after CKPWRGD_PD# transitions from 1 to 0.

(2) To enter the powered-up state with active clock outputs, CLKIN must be active before CKPWRGD_PD# transitions from 0 to 1.

8.4.3 Output Slew Rate Control

The CDCDB800 provides output slew rate control feature which customer can use to compensate for increased output trace length based on their board design. The slew rate of a bank of 4 outputs 0 to 3 and 4 to 7, can be changed within a given range by a SMBus control register called CAPTRIM. Refer to 表 8-15 for more information.

8.4.4 Output Impedance Control

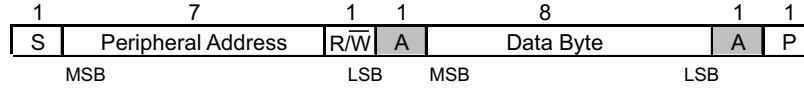
The integrated termination on the CDCDB800 can be programmed either for 85 Ω or 100 Ω. This flexibility ensures that the customer can use the same device across various applications irrespective of the characteristic board impedance which is typically either 85 Ω or 100 Ω. This termination resistor can be changed for all the outputs as whole using bit 5 of a register called OUTSET. Refer to 表 8-13 for more information.

8.5 Programming

The CDCDB800 uses SMBus to program the states of its eight output drivers. See [SMBus](#) for more information on the SMBus programming, and [Register Maps](#) for information on the registers.

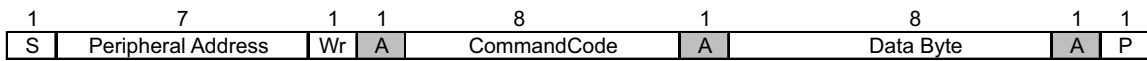
表 8-2. Command Code Definition

BIT	DESCRIPTION
7	0 = <i>Block Read</i> or <i>Block Write</i> operation 1 = <i>Byte Read</i> or <i>Byte Write</i> operation
(6:0)	Register address for <i>Byte</i> operations, or starting register address for <i>Block</i> , operations

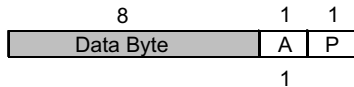
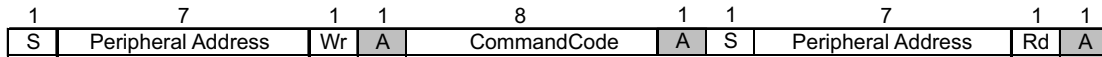


- S** Start Condition
- Sr** Repeated Start Condition
- R/W** 1 = Read (Rd); 0 = Write (Wr)
- A** Acknowledge (ACK = 0 and NACK = 1)
- P** Stop Condition
- Controller-to-Peripheral Transmission
- Peripheral-to-Controller Transmission

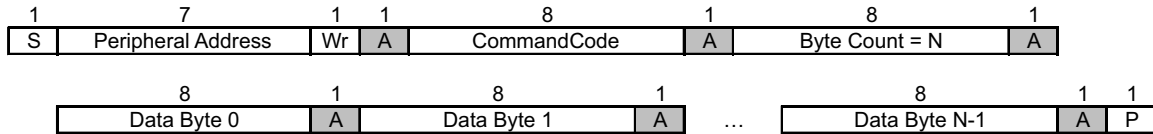
8-2. Generic Programming Sequence



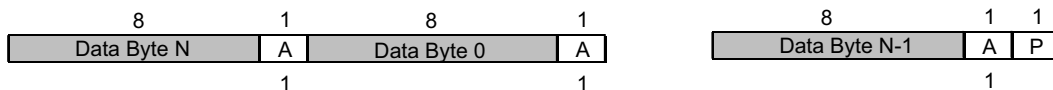
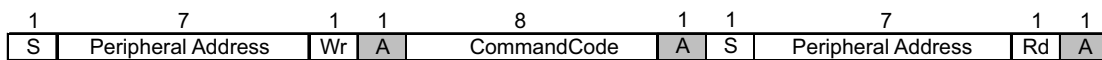
8-3. Byte Write Protocol



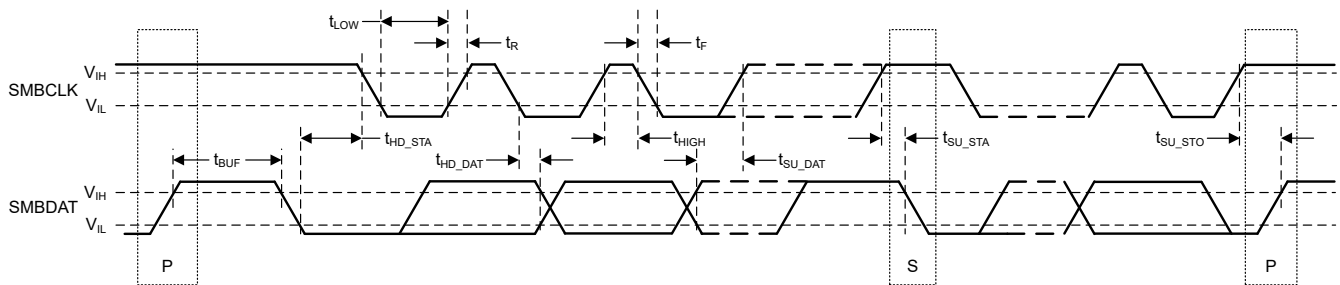
8-4. Byte Read Protocol



8-5. Block Write Protocol



8-6. Block Read Protocol



8-7. SMBus Timing Diagram

8.6 Register Maps

8.6.1 CDCDB800 Registers

表 8-3 lists the CDCDB800 registers. All register locations not listed in 表 8-3 should be considered as reserved locations and the register contents should not be modified.

表 8-3. CDCDB800 Registers

Address	Acronym	Register Name	Section
0h	RCR1	Reserved Control Register 1	Go
1h	OECR1	Output Enable Control 1	Go
2h	OECR2	Output Enable Control 2	Go
3h	OERDBK	Output Enable# Pin Read Back	Go
4h	RCR2	Reserved Control Register 2	Go
5h	VDRREVID	Vendor/Revision Identification	Go
6h	DEVID	Device Identification	Go
7h	BTRDCNT	Byte Read Count Control	Go
8h	OUTSET	Output Setting Control	Go
4Ch	CAPTRIM	Slew Rate Capacitor Cluster 1 & 2	Go

Complex bit access types are encoded to fit into small table cells. 表 8-4 shows the codes that are used for access types in this section.

表 8-4. CDCDB800 Access Type Codes

Access Type	Code	Description
Read Type		
R	R	Read
Write Type		
W	W	Write
Reset or Default Value		
-n		Value after reset or the default value

8.6.1.1 RCR1 Register (Address = 0h) [reset = 47h]

RCR1 is shown in 表 8-5.

Return to the [Summary Table](#).

The RCR1 register contains reserved bits.

表 8-5. RCR1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	Reserved	R	4h	Reserved.
3-0	Reserved	R/W	7h	Writing to these bits will not affect the functionality of the device.

8.6.1.2 OECR1 Register (Address = 1h) [reset = FFh]

OECR1 is shown in [OECR1 Register Field Descriptions](#).

Return to the [Summary Table](#).

The OECR1 register contains bits that enable or disable individual output clock channels [5:0].

表 8-6. OECR1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	OUT_EN_CLK5	R/W	1h	This bit controls the output enable signal for output channel CK5_P/ CK5_N. 0h = Output Disabled 1h = Output Enabled
6	OUT_EN_CLK4	R/W	1h	This bit controls the output enable signal for output channel CK4_P/ CK4_N. 0h = Output Disabled 1h = Output Enabled
5	OUT_EN_CLK3	R/W	1h	This bit controls the output enable signal for output channel CK3_P/ CK3_N. 0h = Output Disabled 1h = Output Enabled
4	OUT_EN_CLK2	R/W	1h	This bit controls the output enable signal for output channel CK2_P/ CK2_N. 0h = Output Disabled 1h = Output Enabled
3	Reserved	R/W	1h	Writing to this bit will not affect the functionality of the device.
2	OUT_EN_CLK1	R/W	1h	This bit controls the output enable signal for output channel CK1_P/ CK1_N. 0h = Output Disabled 1h = Output Enabled
1	OUT_EN_CLK0	R/W	1h	This bit controls the output enable signal for output channel CK0_P/ CK0_N. 0h = Output Disabled 1h = Output Enabled
0	Reserved	R/W	1h	Writing to this bit will not affect the functionality of the device.

8.6.1.3 OECR2 Register (Address = 2h) [reset = 0Fh]

OECR2 is shown in [OECR2 Register Field Descriptions](#).

Return to the [Summary Table](#).

The OECR2 register contains bits that enable or disable individual output clock channels [7:6].

表 8-7. OECR2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-3	Reserved	R/W	1h	Writing to these bits will not affect the functionality of the device.
2	OUT_EN_CLK7	R/W	1h	This bit controls the output enable signal for output channel CK7_P/ CK7_N. 0h = Output Disabled 1h = Output Enabled
1	Reserved	R/W	1h	Writing to this bit will not affect the functionality of the device.
0	OUT_EN_CLK6	R/W	1h	This bit controls the output enable signal for output channel CK6_P/ CK6_N. 0h = Output Disabled 1h = Output Enabled

8.6.1.4 OERDBK Register (Address = 3h) [reset = 0h]

OERDBK is shown in [表 8-8](#).

Return to the [Summary Table](#).

The OERDBK register contains bits that report the current state of the OE[7:0]# input pins.

表 8-8. OERDBK Register Field Descriptions

Bit	Field	Type	Reset	Description
7	RB_OE7	R	0h	This bit reports the logic level present on the OE7# pin.
6	RB_OE6	R	0h	This bit reports the logic level present on the OE6# pin.
5	RB_OE5	R	0h	This bit reports the logic level present on the OE5# pin.
4	RB_OE4	R	0h	This bit reports the logic level present on the OE4# pin.
3	RB_OE3	R	0h	This bit reports the logic level present on the OE3# pin.
2	RB_OE2	R	0h	This bit reports the logic level present on the OE2# pin.
1	RB_OE1	R	0h	This bit reports the logic level present on the OE1# pin.
0	RB_OE0	R	0h	This bit reports the logic level present on the OE0# pin.

8.6.1.5 RCR2 Register (Address = 4h) [reset = 0h]

RCR2 is shown in [RCR2 Register Field Descriptions](#).

Return to the [Summary Table](#).

The RCR2 register contains reserved bits.

表 8-9. RCR2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	Reserved	R	0h	Reserved.

8.6.1.6 VDRREVID Register (Address = 5h) [reset = 0Ah]

VDRREVID is shown in [表 8-10](#).

Return to the [Summary Table](#).

The VDRREVID register contains a vendor identification code and silicon revision code.

表 8-10. VDRREVID Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	REV_ID	R	0h	Silicon revision code. Silicon revision code bits [3:0] map to register bits [7:4] directly.
3-0	VENDOR_ID	R	Ah	Vendor identification code. Vendor ID bits [3:0] map to register bits [3:0] directly.

8.6.1.7 DEVID Register (Address = 6h) [reset = E7h]

DEVID is shown in [表 8-11](#).

Return to the [Summary Table](#).

The DEVID register contains a device identification code.

表 8-11. DEVID Register Field Descriptions

Bit	Field	Type	Reset	Description
7-0	DEV_ID	R	E7h	Device ID code. Device ID bits[7:0] map to register bits[7:0] directly.

8.6.1.8 BTRDCNT Register (Address = 7h) [reset = 8h]

BTRDCNT is shown in [表 8-12](#).

Return to the [Summary Table](#).

The BTRDCNT register contains bits [4:0] which configure the number of bytes which will be read back.

表 8-12. BTRDCNT Register Field Descriptions

Bit	Field	Type	Reset	Description
7-5	Reserved	R/W	0h	Writing to these bits will not affect the functionality of the device.
4	BYTE_COUNTER	R/W	0h	Writing to this register configures how many bytes will be read back.
3-0	BYTE_COUNTER	R/W	8h	

8.6.1.9 OUTSET Register (Address = 8h) [reset = 0h]

OUTSET is shown in [表 8-13](#).

Return to the [Summary Table](#).

Bit5 of the OUTSET register sets the termination for all the outputs while bit4 can be used to set the power-down state for all outputs. The remaining bits for this register are reserved.

表 8-13. OUTSET Register Field Descriptions

Bit	Field	Type	Reset	Description
7-6	Reserved	R	0h	Reserved.
5	CH_ZOUT_SEL	R/W	0h	Select between 85 Ω (0) and 100 Ω (1) Output impedance
4	d_DRIVE_OP_STATE_CTRL	R/W	0h	Power-down state of all output clocks. 0: LOW/LOW 1: TRI_STATE
3-0	Reserved	R/W	0h	Register bits can be written to 0. Writing a different value than 0 will affect device functionality.

8.6.1.10 CAPTRIM Register (Address = 4Ch) [reset = 66h]

CAPTRIM is shown in [表 8-15](#).

Return to the [Summary Table](#).

Bits [7:4] of the CAPTRIM register is used to control the slew rate for output channel cluster 2. Bits [3:0] control the slew rate for output channel cluster 1. Refer below for cluster identification.

表 8-14. Cluster Identification

Cluster	Outputs
1	CK3, CK2, CK1, CK0
2	CK7, CK6, CK5, CK4

表 8-15. CAPTRIM Register Field Descriptions

Bit	Field	Type	Reset	Description
7-4	CLUSTER2_CAP_TRIM	R/W	6h	Slew Rate Reduction Cap Trim for Cluster 2. Default value of 6h. 0: minimum F: maximum
3-0	CLUSTER1_CAP_TRIM	R/W	6h	Slew Rate Reduction Cap Trim for Cluster 1. Default value of 6h. 0: minimum F: maximum

9 Application and Implementation

Note

以下のアプリケーション情報は、TI の製品仕様に含まれるものではなく、TI ではその正確性または完全性を保証いたしません。個々の目的に対する製品の適合性については、お客様の責任で判断していただくこととなります。お客様は自身の設計実装を検証しテストすることで、システムの機能を確認する必要があります。

9.1 Application Information

The CDCDB800 is a fanout buffer that supports PCIe generation 4 and PCIe generation 5 REFCLK distribution. The device is used to distribute up to eight copies of a typically 100-MHz clock.

9.2 Typical Application

図 9-1 shows a CDCDB800 typical application. In this application, a clock generator provides a 100-MHz reference to the CDCDB800 which then distributes that clock to PCIe endpoints. The clock generator may be a discrete clock generator like the CDCI6214 or it may be integrated in a larger component such as a Platform Controller Hub (PCH) or application processor.

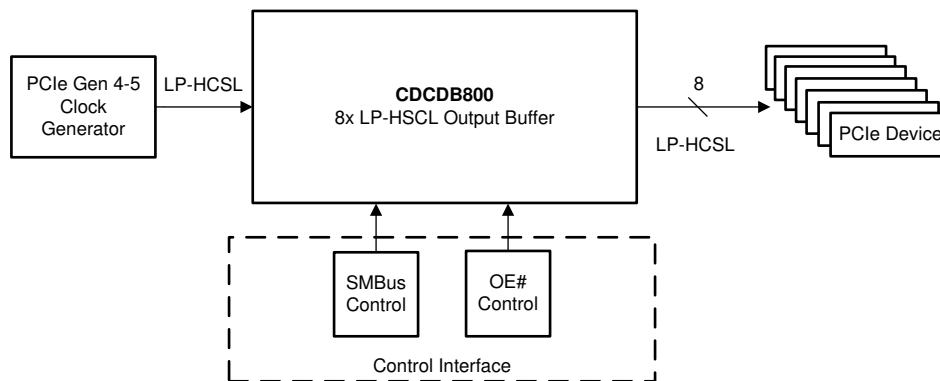


図 9-1. Typical Application

9.2.1 Design Requirements

Consider a typical server motherboard application which must distribute a 100-MHz PCIe reference clock from the PCH of a processor chipset to multiple endpoints. An example of clock input and output requirements is:

- Clock Input:
 - 100-MHz LP-HCSL
- Clock Output:
 - 2x 100-MHz to processors, LP-HCSL
 - 3x 100-MHz to riser/retimer, LP-HCSL
 - 3x 100-MHz to DDR memory controller, LP-HCSL

9.2.2 Detailed Design Procedure

The following items must be determined before starting design of a CDCDB800 socket:

- Output Enable Control Method

9.2.2.1 Output Enable Control Method

The device provides an option to either use SMBus programmed registers (software) to control the outputs or by using the hardware OE# pins. In case of using software to control the outputs, the hardware OE# pins can be left floating as each of these pins have a pulldown to ground. Refer to 表 8-1 and the [Register Maps](#) section for more information on programming the register.

When the user wants to control the outputs with the hardware OE# pins, they can do so for example by connecting these pins to a GPIO controller and follow the [Pin Configuration and Functions](#) section to set the outputs to HIGH/LOW. The bits OUT_EN_CLK7 to OUT_EN_CLK0 used to control the outputs are shown in registers OECR1 (表 8-6) and OECR2 (表 8-7). These register bits are set to 1 by default to ensure that the outputs are "software enabled" and their state is therefore set by hardware OE# pins.

9.2.3 Application Curves

图 6-1 in the [Typical Characteristics](#) section can be used as both an application curve and a typical characteristics plot in this example.

The 图 9-2 and 图 9-3 show characterization data for the Output slew rate for various CAPTRIM codes and across temperature. Customers can use these plots as reference for choosing the appropriate output slew rate based on their system requirement.

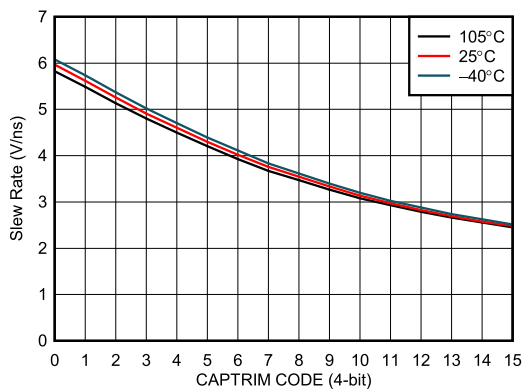


图 9-2. Output Slew Rate vs. CAPTRIM Code

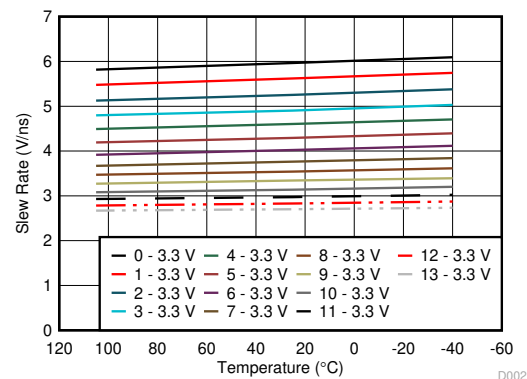


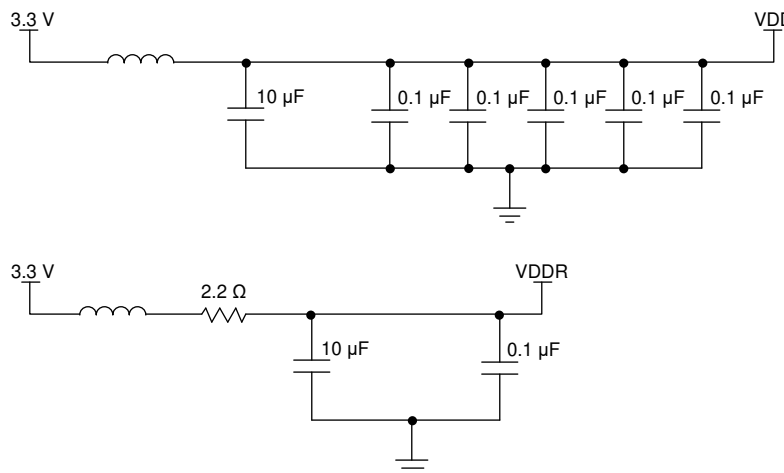
图 9-3. Slew Rate Variation Across Temperature for Different CAPTRIM Code

10 Power Supply Recommendations

High-performance clock buffers are sensitive to noise on the power supply, which can dramatically increase the additive jitter of the buffer. Thus, it is essential to reduce noise from the system power supply, especially when the jitter and phase noise is critical to applications.

Filter capacitors are used to eliminate the low-frequency noise from the power supply, where the bypass capacitors provide the very low impedance path for high-frequency noise and guards the power-supply system against induced fluctuations. These bypass capacitors also provide instantaneous current surges as required by the device and should have low equivalent series resistance (ESR). To properly use the bypass capacitors, place the capacitors very close to the power-supply terminals and lay out with short loops to minimize inductance. TI recommends to insert a ferrite bead between the board power supply and the chip power supply that isolates the high-frequency switching noises generated by the clock buffer. These beads prevent the switching noise from leaking into the board supply. It is imperative to choose an appropriate ferrite bead with very low DC resistance to provide adequate isolation between the board supply and the chip supply, as well as to maintain a voltage at the supply terminals that is greater than the minimum voltage required for proper operation.

☒ 10-1 shows the recommended power supply filtering and decoupling method.



☒ 10-1. Power Supply Decoupling

11 Layout

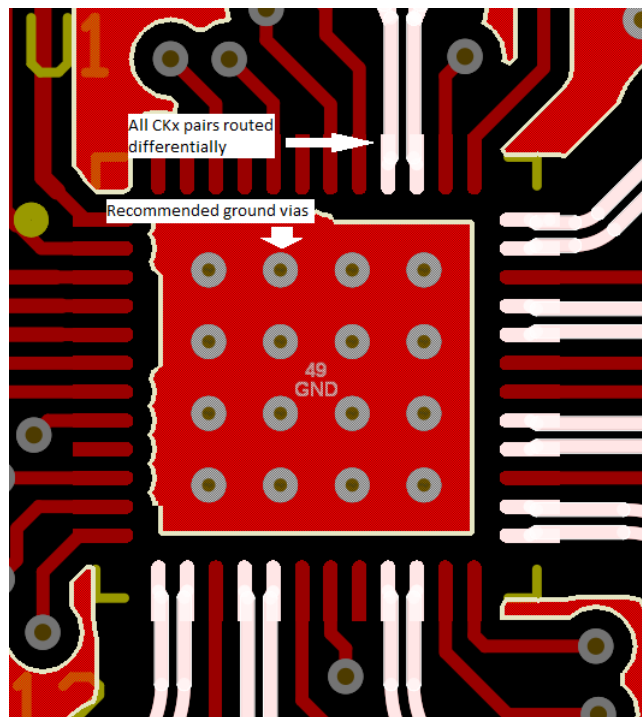
11.1 Layout Guidelines

The following section provides the layout guidelines to ensure good thermal performance and power supply connections for the CDCDB800.

In [Layout Examples](#), the CDCDB800 has 85- Ω differential output impedance LP-HCSL format drivers as per register default settings. All transmission lines connected to CKx pins should be 85- Ω differential impedance, 42.5- Ω single-ended impedance to avoid reflections and increased radiated emissions. If 100- Ω output impedance is enabled, the transmission lines connected to CKx pins should be 100- Ω differential impedance, 50- Ω single-ended impedance. Take care to eliminate or reduce stubs on the transmission lines.

11.2 Layout Examples

[11-1](#) through [11-3](#) are printed circuit board (PCB) layout examples that show the application of thermal design practices and a low-inductance ground connection between the device DAP and the PCB.



[11-1](#). PCB Layout Example for CDCDB800, Top layer

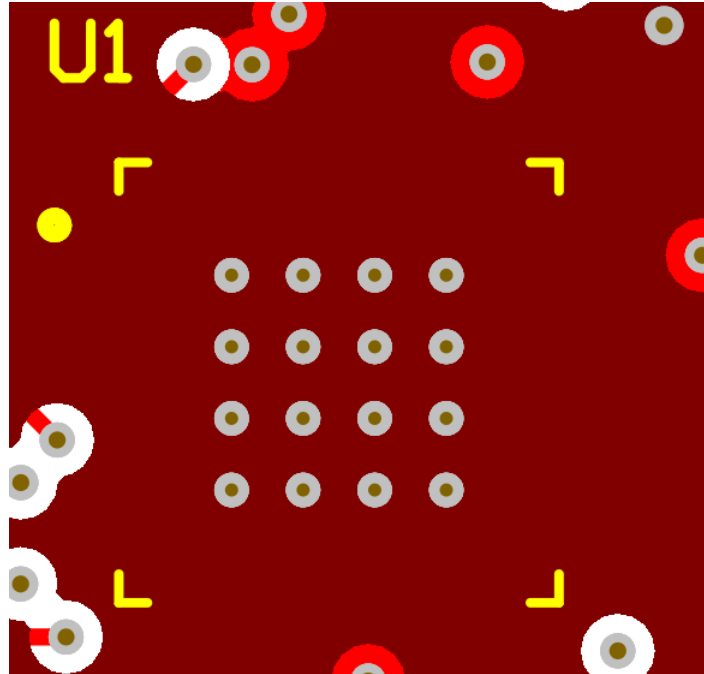


图 11-2. PCB Layout Example for CDCDB800, GND Layer

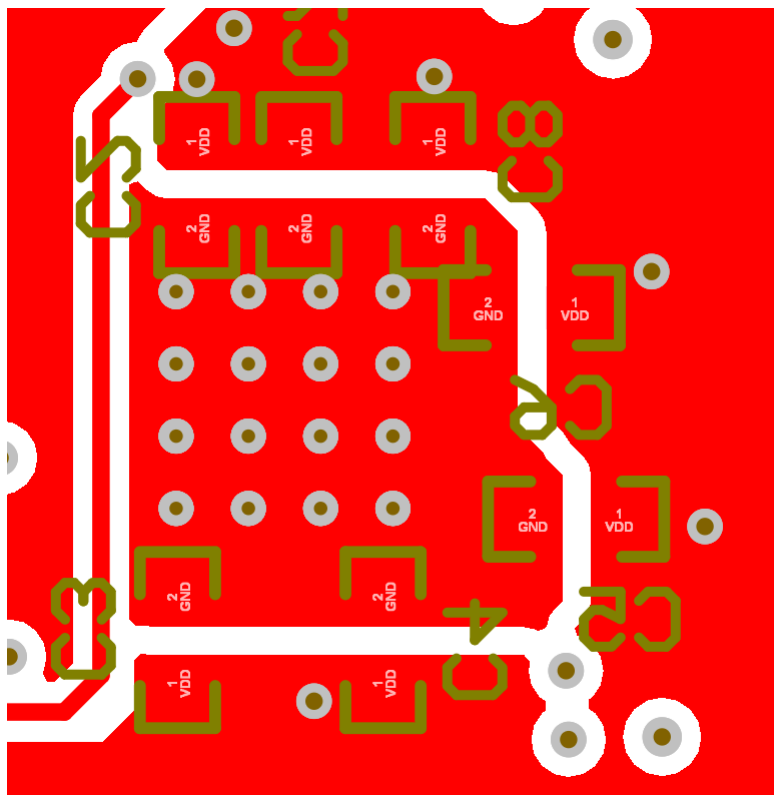


图 11-3. PCB Layout Example for CDCDB800, Bottom Layer

12 Device and Documentation Support

12.1 Device Support

12.1.1 TICS Pro

TICS Pro is an offline software tool for EVM programming and also for register map generation to program a device configuration for a specific application. For TICS Pro, go to <https://www.ti.com/tool/TICSPRO-SW>.

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on [ti.com](https://www.ti.com). Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 サポート・リソース

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12.4 Trademarks

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12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CDCDB800RSLR	ACTIVE	VQFN	RSL	48	4000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 105	CDCB800	Samples
CDCDB800RSLT	ACTIVE	VQFN	RSL	48	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 105	CDCB800	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSELETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CDCDB800RSLR	VQFN	RSL	48	4000	330.0	16.4	6.3	6.3	1.1	12.0	16.0	Q2
CDCDB800RSLT	VQFN	RSL	48	250	180.0	16.4	6.3	6.3	1.1	12.0	16.0	Q2

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CDCDB800RSLR	VQFN	RSL	48	4000	367.0	367.0	35.0
CDCDB800RSLT	VQFN	RSL	48	250	210.0	185.0	35.0

GENERIC PACKAGE VIEW

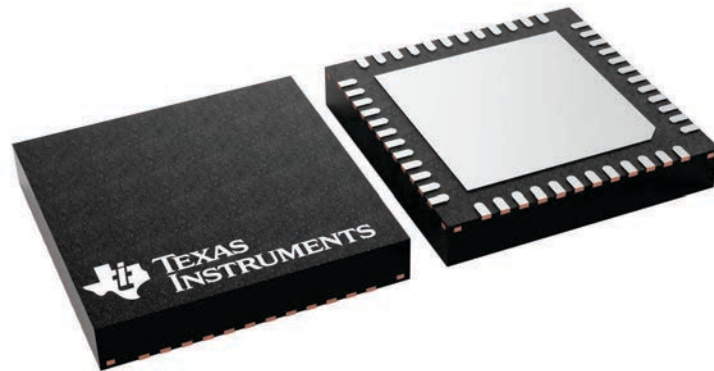
RSL 48

VQFN - 1 mm max height

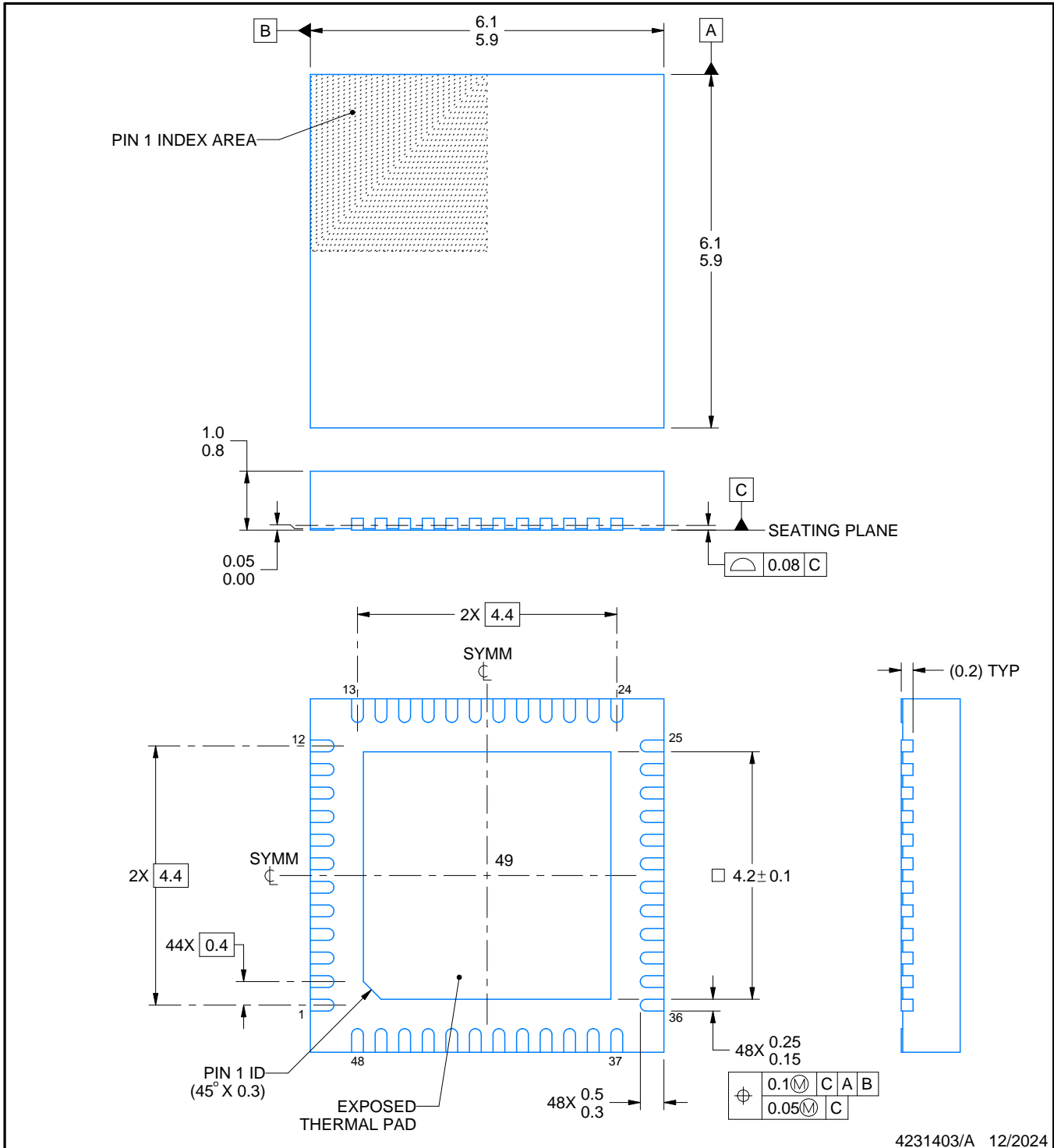
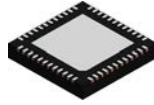
6 x 6, 0.4 mm pitch

QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



4225749/A



NOTES:

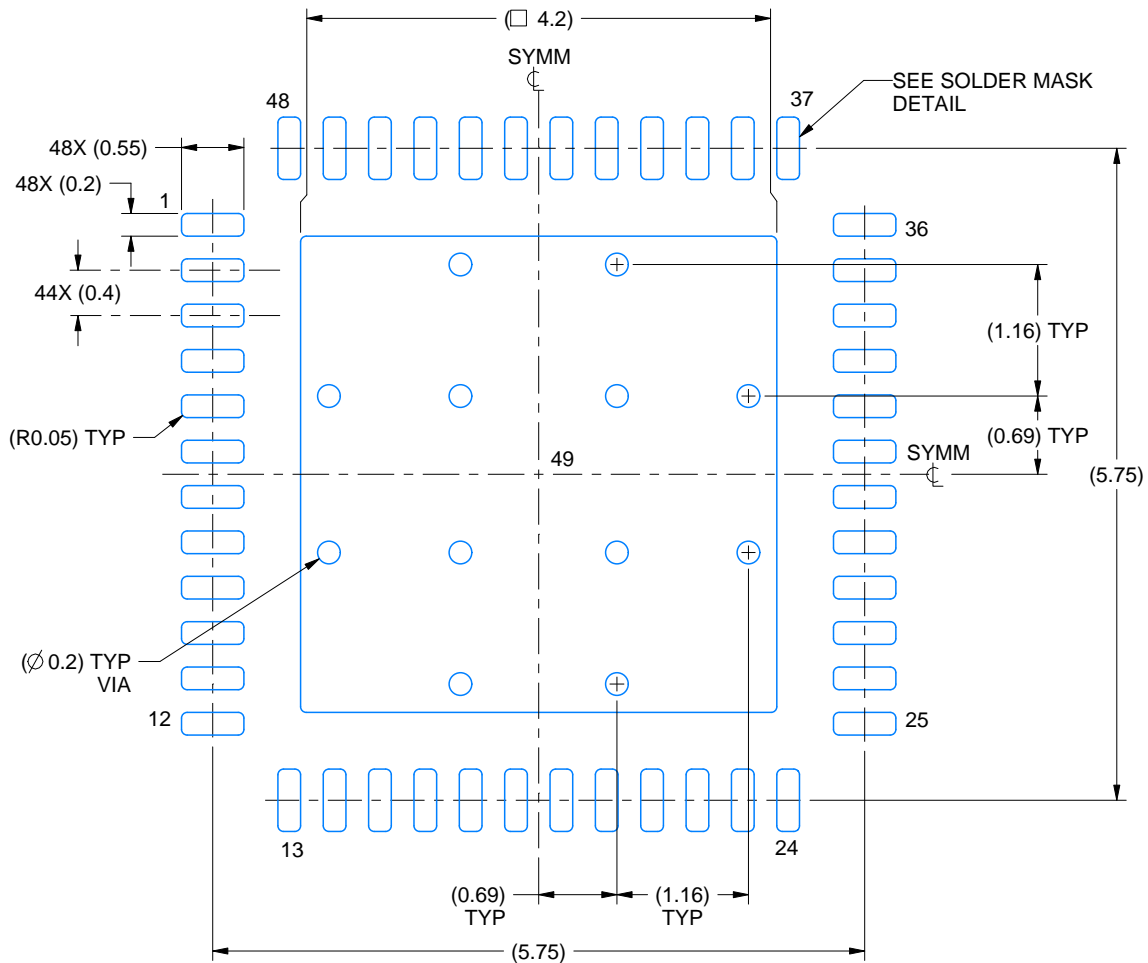
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

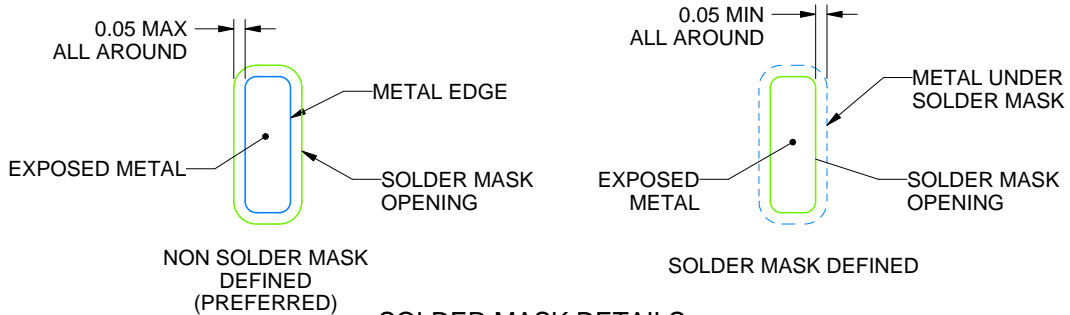
RSL0048G

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 15X



SOLDER MASK DETAILS

4231403/A 12/2024

NOTES: (continued)

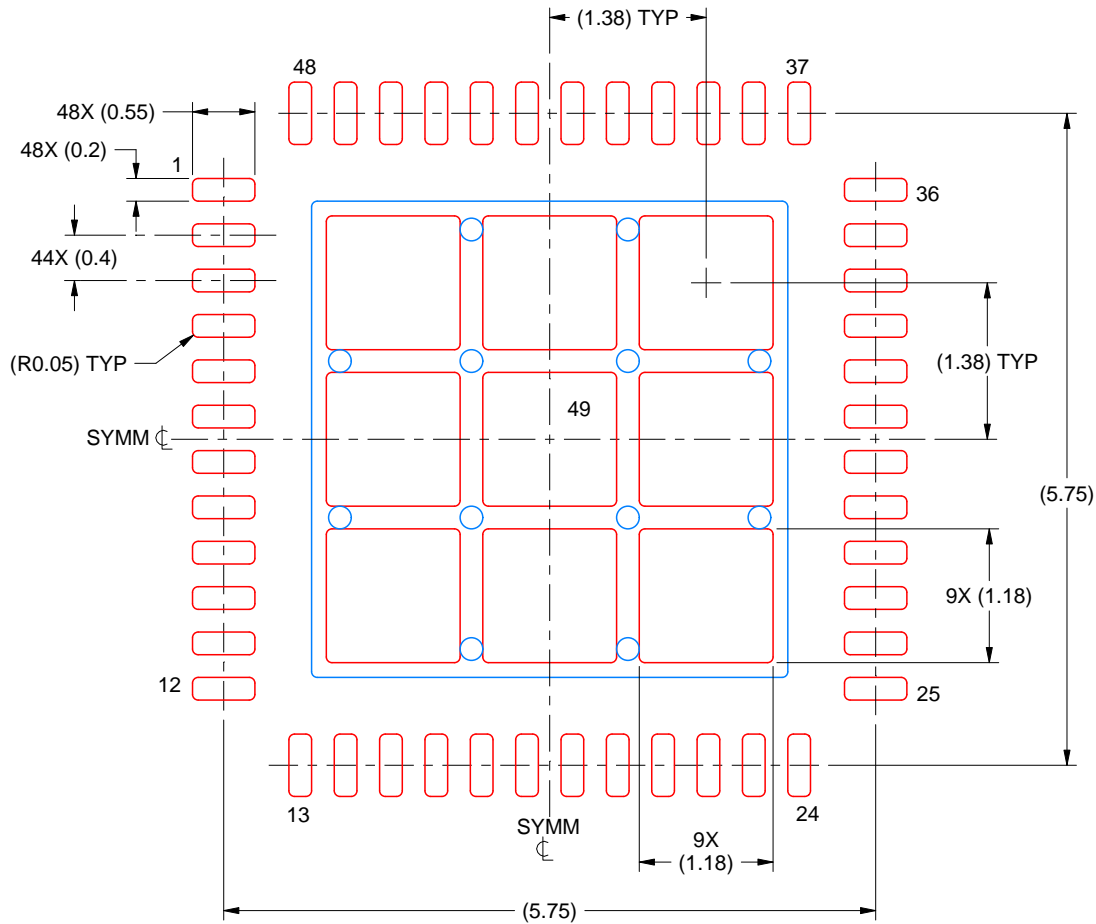
- This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

RSL0048G

VQFN - 1 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



SOLDER PASTE EXAMPLE
 BASED ON 0.1 MM THICK STENCIL
 SCALE: 15X

EXPOSED PAD 49
 71% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE

4231403/A 12/2024

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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